

**Search Notes**

Application/Control No.

10/688,791

Examiner

Bin Shen

Applicant(s)/Patent under  
Reexamination

TEICH ET AL.

Art Unit

1657

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated search.	1/25/2007	BS